

Abstracts

Experimental Measurement of Microstrip Transistor Package Parasitic Reactance (Comments)

H. Beneking. "Experimental Measurement of Microstrip Transistor Package Parasitic Reactance (Comments)." 1978 Transactions on Microwave Theory and Techniques 26.1 (Jan. 1978 [T-MTT]): 43-43.

In the above paper, Akello et al. describe a method for experimental determination of the parasitic of microstrip-transistor packages, based on a resonance principle. A different method of measuring small reactances and susceptances, also permitting the determination of transistor-package elements based on time-domain techniques, is given by Piller in [1]. This method avoids the difficulties resulting from critical coaxial to microstrip transitions.

 [Return to main document.](#)